

**Search Notes**

Application/Control No.

10/539,870

Examiner

Son T. Nguyen

Applicant(s)/Patent under  
Reexamination

IWAKI ET AL.

Art Unit

3643

**SEARCHED**

Class	Subclass	Date	Examiner
119	416-419 452	1/17/2007	STN
	453 480		
	482 496		
	497 28.5		
	165 167		
	170 169		
	347 483		
	161 166		
	171 172		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IPC foreign search: A01K 1/015, 1/035, 31/14, 31/18, 1/00, 1/01, 1/02, 29/00	1/17/2007	STN
text search, see printouts	1/17/2007	STN